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(54) Title: A DEVICE AND METHOD FOR CORRECTING DEFECTS IN X-RAY IMAGES
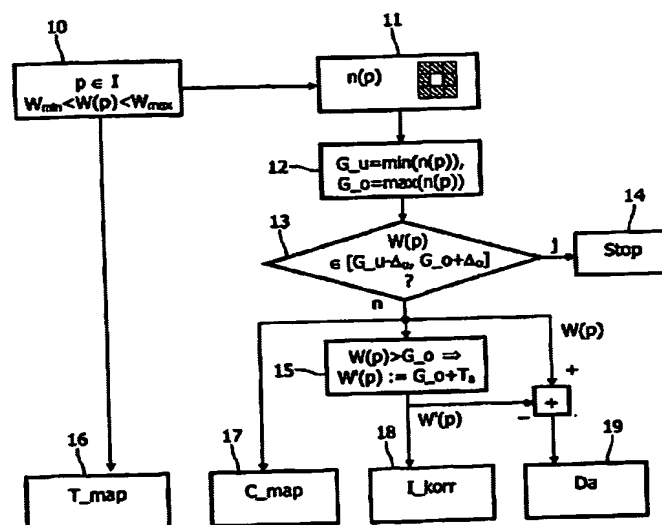
(57) Abstract: The invention relates to a method for correcting defects in X-ray images in which potentially defective picture elements (p) are identified in X-ray images (I), which are created during normal operation, by comparing the value (W(p)) of said picture elements with corresponding values in a neighborhood (n(p)). If a picture element (p) has been classified as "potentially defective" in more than a specified percentage of X-ray images, it is entered in a defect map which is refreshed on a continuous basis. The defect map can then be used to correct other X-ray images.